

Patent claims:

(Original)

1. A device for measuring the thickness of a transparent sample (2), in particular a glass strip or
5 a glass pane,

having a first light beam (L1), in particular a first laser beam, incident on the front surface (8) of the sample (2) obliquely at a first incident angle (α_1),
10

having a second light beam (L2), in particular a second laser beam, incident on the front surface (8) of the sample (2) obliquely at a second incident angle (α_2),

15 the first incident angle (α_1) and the second incident angle (α_2) being different,

and having at least one detector (11, 12) for detecting the light beams (L1', L1'', L2', L2'') of the first and
20 second incident light beams (L1, L2) reflected by the sample (2), and for determining their position, characterized in that

at least one incident light beam (L3) substantially
25 parallel to the first or second light beam (L1, L2) is directed toward the front surface (8) of the sample (2), and in that

at least one detector (11) is provided for detecting a
30 light beam (L3'), reflected by the sample (2), of the parallel light beam (L3), and for determining its position.

(Original)

2. The device as claimed in claim 1, characterized in
35 that the third light beam (L3) can be switched off.

(currently amended)

3. The device as claimed in claim 1 ~~or 2~~, characterized in that the incident light beams (L1, L2,

L3) and/or the reflected light beams (L1', L1'', L2', L2'', L3') lie in a common beam plane (14).

(currently amended)

4. The device as claimed in ~~one of the preceding~~
5 ~~claims,~~ ^{*claim 1*} characterized in that the device (1) and the transparent sample (2) are moved relative to one another.

(currently amended)

5. The device as claimed in ~~claims 3 and 4,~~ ^{*claim 3*}
10 characterized in that the relative direction of movement (15) lies in the common beam plane (14) of the incident light beams (L1, L2, L3) and/or of the reflected light beams (L1', L1'', L2', L2'', L3').

(currently amended)

15 6. The device as claimed in ~~one of the preceding~~
~~claims,~~ ^{*claim 1*} characterized in that the first incident angle (α_1) and the second incident angle (α_2) lie in the beam plane (14), defined by the first and second light beams (L1, L2), on different sides referred to the sample
20 normal (9) in the region of incidence (10).

(currently amended)

7. The device as claimed in ~~one of the preceding~~
~~claims,~~ ^{*claim 1*} characterized in that two detectors (11, 12) are arranged at a spacing from one another, preferably
25 perpendicular to the surface (8) of the sample (2).

(currently amended)

8. The device as claimed in ~~one of the preceding~~
~~claims,~~ ^{*claim 1*} characterized in that the region of incidence (10) of the incident first, second and third light
30 beams (L1, L2, L3) on the sample (2) is smaller than the spacing of two opposite detectors for detecting the reflected light beams (L1', L1'', L2', L2'', L3').

(currently amended)

9. The device as claimed in ~~one of the preceding~~
35 ~~claims,~~ ^{*claim 1*} characterized by two beam splitters (3, 4) for producing the three light beams (L1, L2, L3) from one light beam (L).

(currently amended)

10. The device as claimed in ~~one of the preceding~~
~~claims,~~ ^{*claim 1*} characterized by an evaluation device,
connected to the at least one detector (11, 12), for
determining the thickness of the sample (2), an
5 inclination correction, an angle correction and/or a
curvature correction being carried out, in particular.

(currently amended)

11. A method for measuring the thickness of a
transparent sample (2), in particular having a device
10 (1) as claimed in ~~claims 1 to 9,~~ *claim 1*

in which a first light beam (L1) is incident obliquely
on the front surface (8) of the sample (2) at a first
incident angle (α_1), and the positions of the light
15 beam (L1') reflected at the front surface (8) and of
the light beam (L1'') reflected at the rear surface
(13) are determined,

in which a second light beam (L2) is incident obliquely
20 on the front surface (8) of the sample (2) at a second
incident angle (α_2), different from the first incident
angle (α_1), and the positions of the light beam (L2')
reflected at the front surface (8) and of the light
beam (L2'') reflected at the rear surface (13) are
25 determined,

the thickness of the transparent sample (2) being
determined from the spacing of the light beams (L1',
L1'', L2', L2''), reflected at the front surface (8)
30 and the rear surface (13), of the first light beam (L1)
and/or of the second light beam (L2), and

an inclination and/or wedge angle correction being
carried out by comparing the positions of at least a
35 portion of the reflected light beams (L1', L1'', L2',
L2''), characterized in that

at least a third light beam (L3) is incident obliquely on the front surface (8) at a known spacing (s) substantially parallel to the first or second light beam (L2), and a curvature correction is carried out by determining the positions of the light beams (L2', L3'), respectively reflected at the front surface (8) and at the rear surface (13), of these parallel light beams (L2, L3).

(original)
10 12. The method as claimed in claim 11, characterized in that the first light beam (L1) and the second light beam (L2) are incident from different sides on the front surface (8) of the sample (2) in the beam plane (14), defined by them, referred to the sample normal (9) in the region of incidence (10).

(original)
13. The method as claimed in claim 12, characterized in that the first and the second incident angles (α_1 , α_2) are equal in absolute value and are preferably 45° .

(correctly amended) claim 11
20 14. The method as claimed in ~~one of claims 11 to 13~~, characterized in that the spacing from the sample (2) is determined in each case from the position of the light beams (L1', L2') preferably reflected at the front surface (8) for the purpose of the inclination and/or wedge angle correction, a wedge angle or an inclination correction being undertaken when spacings do not correspond.

(original)
30 15. The method as claimed in claim 14, characterized in that a wedge or inclination angle (δ , σ) is determined from a non-corresponding spacing of the reflected light beams.

(correctly amended) claim 11
35 16. The method as claimed in ~~one of claims 11 to 15~~, characterized in that the spacing between the reflected light beams (L3', L2') of the third light beam (L3) and the first or second light beam (L2) substantially

parallel thereto is determined and, if appropriate, a curvature correction is carried out.

(original)

- 5 17. The method as claimed in claim 16, characterized in that the radius of curvature (R) and/or angle of curvature are/is determined from the spacing between the reflected light beams (L3', L2') of the third light beam (L3) and the first or second light beam (L2) substantially parallel thereto.

10 *(original)*

18. The method as claimed in claim 17, characterized in that the refractive power is determined from the radius of curvature (R).